

STL22NF10

N-CHANNEL 100V - 0.055 Ω - 22A PowerFLAT™ LOW GATE CHARGE STripFET™ II MOSFET

| TYPE | V _{DSS} | R _{DS(on)} | I _D |
|-----------|------------------|---------------------|----------------|
| STL22NF10 | 100 V | <0.060 Ω | 22 A(1) |

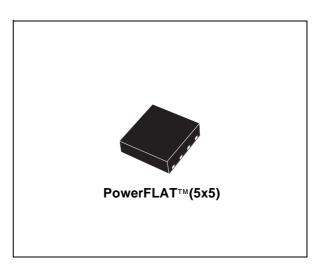
- TYPICAL $R_{DS}(on) = 0.055 \Omega$
- IMPROVED DIE-TO-FOOTPRINT RATIO
- VERY LOW PROFILE PACKAGE (1mm MAX)
- VERY LOW THERMAL RESISTANCE
- VERY LOW GATE CHARGE



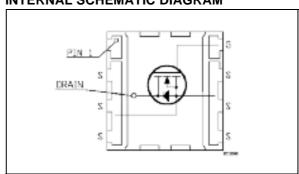
This application specific Power MOSFET is the second generation of STMicroelectronis unique "STripFET™" technology. The resulting transistor shows extremely low on-resistance and minimal gate charge. The new PowerFLAT™ package allows a significant reduction in board space without compromising performance.

APPLICATIONS

- HIGH-EFFICIENCY ISOLATED DC-DC CONVERTERS
- TELECOM AND AUTOMOTIVE



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | Value | Unit |
|----------------------|--|------------|------|
| V _{DS} | Drain-source Voltage (V _{GS} = 0) | 100 | V |
| V _{DGR} | Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$) | 100 | V |
| V _{GS} | Gate- source Voltage | ± 20 | V |
| I _D (2) | Drain Current (continuous) at T _C = 25°C (Steady State) | 5.3 | А |
| I _D (2) | Drain Current (continuous) at T _C = 100°C | 3.8 | А |
| I _{DM} (3) | Drain Current (pulsed) | 22 | A |
| P _{tot} (2) | Total Dissipation at T _C = 25°C (Steady State) | 4 | W |
| P _{tot} (1) | Total Dissipation at T _C = 25°C | 70 | W |
| | Derating Factor | 0.03 | W/°C |
| dv/dt (5) | Peak Diode Recovery voltage slope | 16 | V/ns |
| E _{AS} (6) | Single Pulse Avalanche Energy | 82 | mJ |
| T _{stg} | Storage Temperature | -55 to 150 | |
| Tj | Operating Junction Temperature | 33 10 130 | °C |

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THERMAL DATA

| Rthj-F | (*)Thermal Resistance Junction-Foot (Drain) | 1.8 | °C/W |
|-------------|---|------|------|
| Rthj-pcb(4) | Thermal Operating Junction-pcb | 31.5 | °C/W |

^(*) Mounted on FR-4 board (t \leq 10 sec.)

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

| Symbol | Parameter | Test Conditions N | | Тур. | Max. | Unit |
|----------------------|--|---|-----|------|---------|----------|
| V _{(BR)DSS} | Drain-source Breakdown Voltage | $I_D = 250 \ \mu\text{A}, \ V_{GS} = 0$ | 100 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current (V _{GS} = 0) | $V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 125^{\circ}C$ | | | 1 10 | μA μA |
| Igss | Gate-body Leakage Current (V _{DS} = 0) | V _{GS} = ± 20 V | | | ±100 | nA |

ON (7)

| Symbol | Parameter | Test Conditions | | Min. | Тур. | Max. | Unit |
|---------------------|-----------------------------------|------------------------|-------------------------|------|-------|-------|------|
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}$ | I _D = 250 μA | 2 | | | V |
| R _{DS(on)} | Static Drain-source On Resistance | V _{GS} = 10 V | I _D = 11 A | | 0.055 | 0.060 | Ω |

DYNAMIC

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|------------------|------|----------------|
| gfs ⁽⁷⁾ | Forward Transconductance | V _{DS} = 20 V I _D = 11 A | | 16 | | S |
| C _{iss} C _{oss} C _{rss} | Input Capacitance Output Capacitance Reverse Transfer Capacitance | $V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$ | | 885 130 56 | | pF pF pF |

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|---------------|------|----------------|
| t _{d(on)} t _r | Turn-on Delay Time Rise Time | $\begin{array}{ccc} V_{DD} = 50 \text{ V} & I_D = 11 \text{ A} \\ R_G = 4.7 \ \Omega & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{array}$ | | 20 45 | | ns ns |
| Q _g Q _{gs} Q _{gd} | Total Gate Charge Gate-Source Charge Gate-Drain Charge | V _{DD} = 80V I _D = 22A V _{GS} =10V | | 30 6 10 | 40 | nC nC nC |

SWITCHING OFF

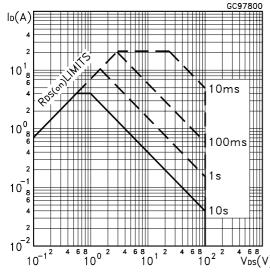
| Symbol | Parameter | Test Conditions | | Min. | Тур. | Max. | Unit |
|---------------------------------------|----------------------------------|-----------------|-------------------------------|------|----------|------|----------|
| t _{d(off)} t _f | Turn-off Delay Time Fall Time | 55 | D = 11 A S = 10 V re 3) | | 45 10 | | ns ns |

SOURCE DRAIN DIODE

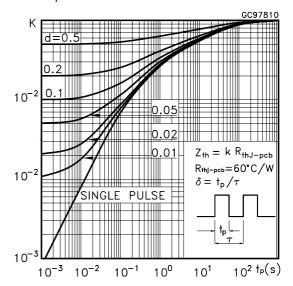
| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|-------------------|-----------|---------------|
| I _{SD} I _{SDM} | Source-drain Current Source-drain Current (pulsed) | | | | 5.3 22 | A A |
| V _{SD} (7) | Forward On Voltage | I _{SD} = 22 A V _{GS} = 0 | | | 1.3 | V |
| t _{rr} Q _{rr} IRRM | Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current | $\begin{split} I_{SD} = & 22 \text{ A} & \text{di/dt} = 100 \text{A/}\mu\text{s} \\ V_{DD} = & 30 \text{ V} & T_j = 150 ^{\circ}\text{C} \\ \text{(see test circuit, Figure 5)} \end{split}$ | | 100 375 7.5 | | ns nC A |

- (1) The value is rated according R_{thj-F}.
 (2) The value is rated according R_{thj-pcb}.
- (3) Pulse width limited by safe operating area.
- (4) When Mounted on FR-4 Board of 1 inch², 2 oz Cu, t<10s.
- (5) $I_{SD} \le 22A$, di/dt $\le 300A/\mu$ s, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$. (6) Starting $T_j = 25$ °C, $I_D = 11$ A, $V_{DD} = 30V$. (7) Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %.

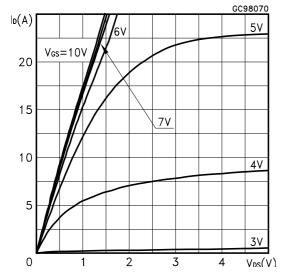
Safe Operating Area



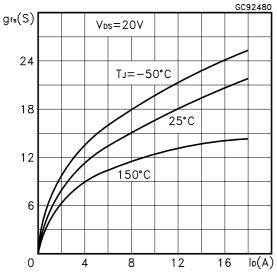
Thermal Impedance



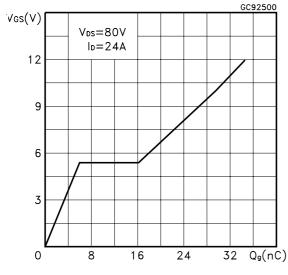
Output Characteristics



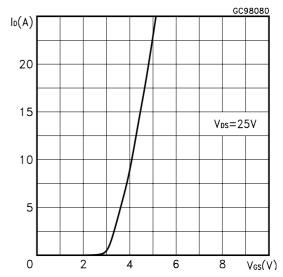
Transconductance



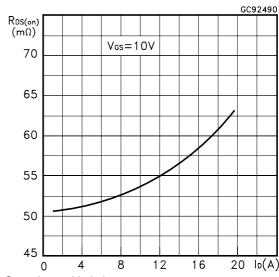
Gate Charge vs Gate-source Voltage



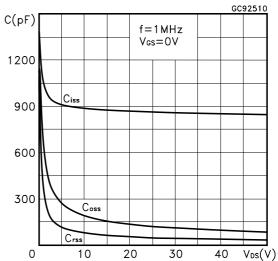
Transfer Characteristics



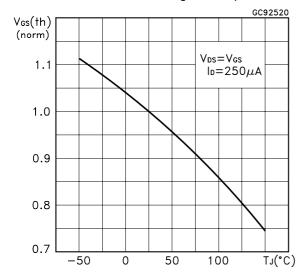
Static Drain-source On Resistance



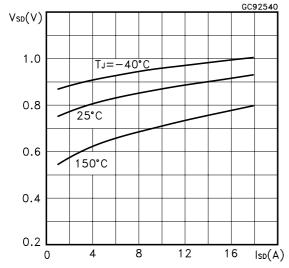
Capacitance Variations



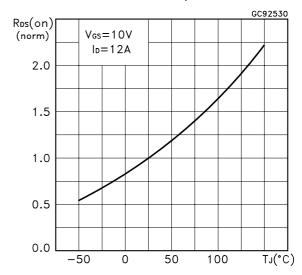
Normalized Gate Threshold Voltage vs Temperature



Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature.

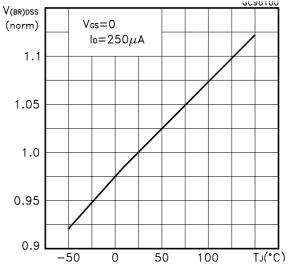


Fig. 1: Unclamped Inductive Load Test Circuit

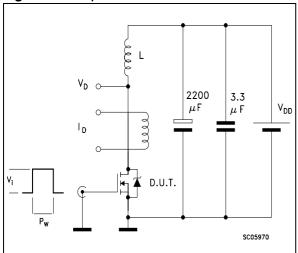


Fig. 3: Switching Times Test Circuits For Resistive Load

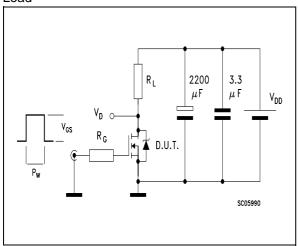


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

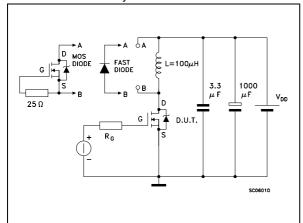


Fig. 2: Unclamped Inductive Waveform

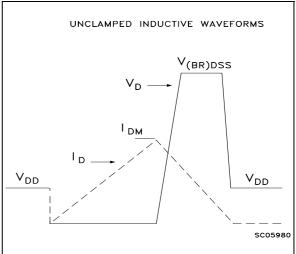
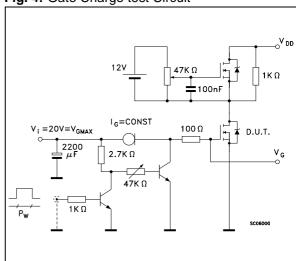
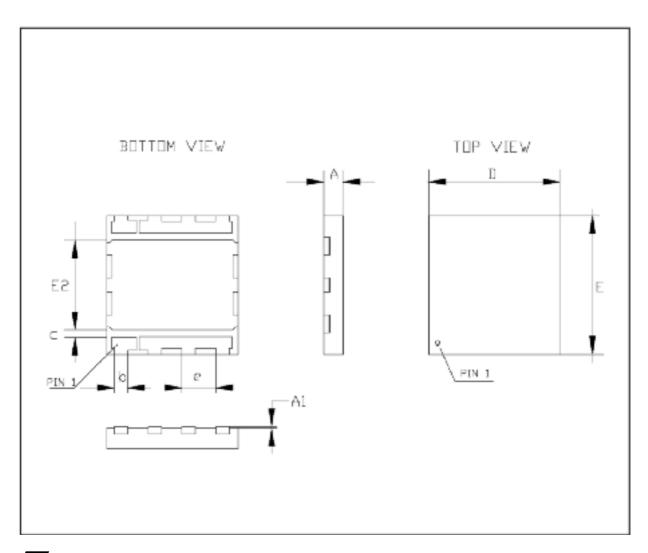


Fig. 4: Gate Charge test Circuit



PowerFLAT™ (5x5) MECHANICAL DATA

| DIM. | mm. | | | inch | | |
|------|------|------|------|-------|-------|-------|
| DIM. | MIN. | TYP | MAX. | MIN. | TYP. | MAX. |
| A | | 0.90 | 1.00 | | 0.035 | 0.039 |
| A1 | | 0.02 | 0.05 | | 0.001 | 0.002 |
| b | 0.43 | 0.51 | 0.58 | 0.017 | 0.020 | 0.023 |
| С | 0.33 | 0.41 | 0.48 | 0.013 | 0.016 | 0.019 |
| D | | 5.00 | | | 0.197 | |
| E | | 5.00 | | | 0.197 | |
| E2 | 3.10 | 3.18 | 3.25 | 0.122 | 0.125 | 0.128 |
| e | | 1.27 | | | 0.050 | |



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